



PATENT APPLICATION

JPW

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Hiroshi HASEGAWA

Group Art Unit: 2163

Application No.: 10/807,392

Examiner: W. LEE

Filed: March 24, 2004

Docket No.: 118833

For: ORIGINALITY GUARANTEE SYSTEM, EMBEDDED INFORMATION/ALTERATION
DETECTION APPARATUS AND EMBEDDED INFORMATION/ALTERATION
DETECTION METHOD, AND RECORD MEDIUM STORING EMBEDDED
INFORMATION/ALTERATION DETECTION PROGRAM THEREIN

SUBMISSION OF REFERENCES

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.97(i), the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached.

- ☒ 1. One or more reference cited herein was cited in an Examination Result issued April 24, 2007 in a counterpart Japanese application. See References 1 & 2.
- ☒ 2. An English language Abstract of one or more non-English language reference is attached. See References 1 & 2.
- ☒ 3. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See References 1 & 2.

Respectfully submitted,

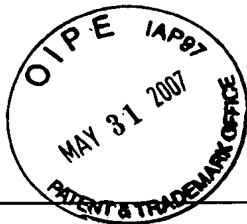
James A. Oliff
Registration No. 27,075

Daniel A. Tanner, III
Registration No. 54,734

JAO:DAT/eks

Date: May 31, 2007
OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
Telephone: (703) 836-6400

DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461
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Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 118833		APPLICATION NO. 10/807,392	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroshi HASEGAWA			
				FILING DATE March 24, 2004		GROUP 2163	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	1	JP 2001-282619 A	10/12/2001	JAPAN	X	X	
	2	JP 10-173646 A	06/26/1998	JAPAN	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: May 31, 2007